Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/728,259	KEPPEL, DAVID S.	
Examiner	Art Unit	
Michael Peffley	3739	

Michael Peffley

	SEAR	CHED	
Class	Subclass	Date	Examiner
606	32-35, 37- 42	6/27/2006	MP
			-
		-	

ראו	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
					
					
	į				

XMF
_